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#### Abstract

Metode za ugotavljanje odstopka od krožnosti - Meritev sprememb polmera

Methods for the assessement of departure from roundness -- Measurement of variations in radius


Méthodes d'évaluation des écarts de circularité -- Mesurage des variations de rayon (standardls.iteh.ai)
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# International Standard 



4291

# Methods for the assessment of departure from roundness - Measurement of variations in radius 

Méthodes d'évaluation des écarts de circularité - Mesurage des variations de rayon

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## Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work.

Draft International Standards adopted by the technical committees are circulated to the member bodies for approval before their acceptance as International Standards by the ISO Council. They are approved in accordance with ISO procedures requiring at least $75 \%$ approval by the member bodies voting. TANDARD PREVINW

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## Methods for the assessment of departure from roundness - Measurement of variations in radius

## 1 Scope and field of application

This International Standard specifies a method for determining
departures from roundness by measuring variations in radius by means of contact (stylus) instruments.

a) types of instruments and general requirements;
digital representation of the profile (generally $7 \%$ to $15 \%$ of its mean radius, see annex E ), the position of the measured section or sections relative to some feature of the workpiece.

ISO 6318, Measurement of roundness - Terms, definitions and parameters of roundness.
b) recommendations forlthe/use of instruments;log/standards/sist/644041 dc-851a-4167-9921-
c) procedures for calibration of instruments and verification of their characteristics.

This International Standard applies to the assessment of the departures from ideal roundness of a workpiece through the medium of a profile transformation, obtained under reference conditions, expressed with respect to any one of the following centres :
a) centre of the least squares circle;
b) centre of the minimum zone circle;
c) centre of the minimum circumscribed circle;
d) centre of the maximum inscribed circle.

Each of these centres may have its own particular application. The position of the least squares centre can be calculated from a simple explicit equation given in annex F .

Departures from roundness of the measured profile, procedure, calibration and determination of systematic errors of rotation are dealt with in annexes $A$ to $D$, respectively. Annex $E$ gives rules for plotting and reading polar graphs.

## NOTES

1 Profile transformation is defined in ISO 6318.
2 Reference conditions include the stylus, frequency limitations of an electric wave filter (if used), permissible eccentricity of the graphical or

For the purposes of this International Standard, the definitions given in ISO 6318 apply.

## 4 Instruments

### 4.1 Instrument types and general requirements

Instruments of the stylus type employed for the determination of departures from ideal roundness may be of one of two types:
a) a stylus and transducer rotating round a stationary workpiece;
b) a rotating workpiece engaged by a stationary stylus and transducer.

According to the nature of the output information, instruments for the measurement of roundness fall into two groups :
a) profile recording;
b) with direct display of the values of the parameters.

Both groups may be combined in one instrument.
Stylus instruments should comply with the requirements of 4.1.1 to 4.1.3.

### 4.1.1 Stylus types and dimensions

The surface characteristics of the part under examination are of primary importance in the choice of stylus. Variations to meet different requirements, depending upon the nature and magnitude of the irregularities which are to be taken into account, are permitted as shown in figures 1 to 4 (see also clause B.3).


Figure 1 - Spherical stylus

The dimensions $r$ and $R$ of the various styli shall be selected from the following values :
$-0,25 ; 0,8 ; 2,5 ; 8$ and 25 mm .

### 4.1.2 Stylus static force

The force shall be adjustable up to $0,25 \mathrm{~N}$ and in use shall be adjusted down to the lowest value that will ensure continuous contact between the stylus and the surface being measured.

### 4.1.3 Instrument response for sinusoidal undulations

The range of periodic sinusoidal undulations per revolution (upr) (i.e. per $360^{\circ}$ ) of the workpiece to which the instrument responds shall be terminated by values taken from the table.

Table - Limiting values of upr

| Filters transmitting from <br> 1 upr up to | Filters rejecting <br> below |
| :---: | :---: |
| 15 | 15 |
| 50 | 50 |
| 150 |  |
| 500 |  |
| 1500 |  |

Figure 2 - Cylindrical stylus

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Figure 3 - Toroidal (hatchet) stylus


Figure 4 - Ovoidal stylus

The response at the rated termination of the band shall be $75 \%$ of the maximum transmission within the band except for 1 upr which represents direct mechanical coupling between input and output. (See note 2c).

The transmission characteristics of the filter shall be equivalent to those produced by two independent C-R ${ }^{1)}$ networks of equal time constant (see figure 5). These curves show only the amplitude attenuation characteristics and do not take phase shift into account. A phase corrected filter of known characteristics giving the same rate of attenuation may be used provided that these characteristics are indicated in the test report.

## NOTES

1 When a filter attenuating high frequencies is required, the two $C-R$ form will generally be acceptable, distortion of the transmitted profile due to phase shift of the high relative to the low frequencies being generally unimportant.
When a filter attenuating low frequencies is required, distortion due to phase shift may be more significant and have to be taken into account, or avoided by using a phase corrected filter.
2a) It is necessary to distinguish clearly between the undulations per revolution (i.e. per $360^{\circ}$ ) of the workpiece and the response of electronic circuits in the instrument in hertz. ${ }^{2)}$
The frequency, in hertz, generated by the instrument will be given by the number of sinusoidal undulations per $360^{\circ}$ of the workpiece multiplied by the number of revolutions per second of the spindle.

2b) Eccentricity will count as 1 upr. A sinusoidal component of 1 upr will be found when the periphery of the workpiece is assessed from a centre other than the centre of the least squares circle.

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Figure 5 - Typical transmissions showing rate of attenuation given by two independent C-R networks of equal time constant

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2c) When electronic circuits of instruments are required tocrespond S. it Cing on a perfectly flat test piece set perfectly perpendicular down to 1 upr, they are often made responsive down to zero frequency $(0 \mathrm{~Hz})$, this being a natural way of avoiding phase distortion and permitting calibration by static means.
to the reference axis of rotation.
NOTE - The components of errors of rotation are vector quantities
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### 4.2 Instrument errors

### 4.2.1 Overall instrument error

This is the difference between the value of the parameter indicated, displayed or recorded by the instrument and the true value of this parameter. The value of this error is determined when measuring a test piece. The overall instrument error shall be expressed as a percentage of the upper limiting value of the measuring range used. This error comprises systematic and random components from the spindle error, electric noise, vibration, magnification, etc.

### 4.2.2 Errors of rotation of the instrument

The errors of rotation are determined under reference conditions at assigned positions of measurement :
a) radial instrument error - the value of the roundness parameter which would be indicated by the instrument when measuring a perfectly round and perfectly centred section of a test piece, in a direction perpendicular to the reference axis of rotation;
b) axial instrument error - the value derived from the zonal parameter displayed by the instrument when measur-

### 4.2.3 Statements of errors of rotation

The rotating member can exhibit, within the confines of its bearings, combinations of
a) radial displacements parallel to itself;
b) axial displacements parallel to itself;
c) tilt.

The magnitude of the radial instrument error, measured at the stylus, depends on the position of the measurement plane along the axis of rotation. The magnitude of the axial instrument error depends on the radius at which the flat test piece is measured. The axial and radial positions selected for test shall therefore be stated.

The radial instrument error shall be expressed at two stated and well separated positions along the axis or at one position together with the rate of change of the radial instrument error along the axis.

The axial instrument error shall be expressed on the axis and at one stated radius.

## Annex A

## Departure from roundness of the measured profile of the workpiece

In this International Standard, the departure from ideal roundness is assessed as the difference between the largest and the smallest radii of the measured profile of the workpiece, measured from one or other of following centres :
a) least squares centre (LSC) - the centre of the least squares mean circle (see figure 6);
b) minimum zone centre ( MZC ) - the centre of the minimum zone circle (see figure 7);
c) minimum circumscribed circle centre (MCC) - the centre of the minimum circumscribed circle for external surfaces (see figure 8);
d) maximum inscribed circle centre (MIC) - the centre of the maximum inscribed circle for internal surfaces (see figure 9 ).

The largest and smallest radii, in each case, are commonly used to define a concentric zone. The width of the zone may be designated by $\Delta Z$, with a subscript denoting its centre. For the purposes of this International Standard, the following subscripts are used :

| least squares | subscript $q$, thus $\Delta Z_{q}$ |
| :--- | :--- |
| minimum width | subscript $z$, thus $\Delta Z_{z}$ |
| minimum circumscribed | subscript c, thus $\Delta Z_{c}$ |
| maximum inscribed | subscript $i$, thus $\Delta Z_{i}$ |

NOTE - The use of circles drawn on the chart to represent circles fitting the profile of the workpiece assumes that the workpiece is sufficiently well centred on the axis of the instrument (see B.1.1, figure 10 and annex F).


Figure 6 - Assessment of roundness from least squares centre, $\Delta Z_{q}$


Figure 7 - Assessment of roundness from minimum zone centre, $\Delta Z_{z}$ SIST ISO 4291:1995
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Figure 8 - Assessment of roundness from centre of minimum circumscribed circle, $\Delta Z_{c}$


Figure 9 - Assessment of roundness from centre of maximum inscribed circle, $\Delta Z_{i}$

## Annex B

## Procedure

(This annex gives general guidance on setting up and measurement.)

## B. 1 Guidance on setting up prior to measurement

The workpiece shall be set up so that the section to be measured is sufficiently well centred on the axis of rotation to avoid excessive distortion due to eccentricity, and with its axis sufficiently parallel to the axis of rotation to avoid excessive inclination errors.

Several kinds of distortion result from polar plotting because, on the chart, only the variations in radius of the workpiece, together with the eccentricity, and not the radius itself, are highly magnified.
B.1.1 In the direction of eccentricity, the radius of the eccentric plot is independent of the eccentricity, but in the perpendicular direction the radius is slightly increased in proportion to the square of the eccentricity (see figure 10). Strictly, the eccentric plot of a perfect circle has the form of a limacton; however, this is hardly perceptible as such when the eccentricity is very small. Graphical compensation is sometimes possbible; compensation by electrical methods is widely practised, and elimination of the distortion by digital correction is in course of development.
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Figure 10 - Slight increase of the radius of the eccentric plot in the perpendicular direction
B.1.2 The circumferential separation of the peaks round a periodic profile is greater than that of the valleys, even though the difference on the workpiece is negligibly small and, to avoid giving a misleading impression, the ratio of peak-to-valley radius measured from the centre of the chart shall not be too great.
B.1.3 Inclination of the axis of the workpiece to the axis of rotation will cause a perfectly round cylinder to appear elliptical. If $D$ is the diameter of the workpiece, $\theta$ the angle of inclination (see figure 11) and $M$ the magnification, the diametral difference on the chart will be $M D(1-\sec \theta)$.

Conversely, appropriate inclination can cause an elliptical cylinder to appear to be round.



[^0]:    1) " $C$ " stands for "capacitive", " $R$ " for "resistive".
    2) $1 \mathrm{~Hz}=1$ cycle per second
